

Application/Control No.	Applicant(s)/Patent under Reexamination NAKANO ET AL.	
Musha Siak	2825	

	SEARCHED				
Class	Subclass	Date	Examiner		
716	2,5,8- 11,19-21	3/30/2005	vs		
430	5,311,313	3/30/2005	vs		
438	57-60	3/30/2005	vs		
438	514	3/30/2005	vs		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
716	19,21	10/5/05	US	
Interfer.	ever Ent	iº/5/05	15	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
(0202002	DATE	EXMR	
EAST ALL DATABASES	3/30/2005	VS	
EAS all databour See Search History Print out	13/5/05	VS	